

Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5240MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5240.0099	5240	0.0099	1.8893
		V max (V)	138.00	5240.0009	5240	0.0009	0.1718
		V min (V)	102.00	5240.0090	5240	0.0090	1.7176
Limits				5150-5250 MHz			
Result				Complies			

Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5240MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5240.0020	5240	0.0020	0.3817
		T (°C)	-10	5240.0070	5240	0.0070	1.3359
		T (°C)	0	5240.0004	5240	0.0004	0.0763
		T (°C)	10	5240.0090	5240	0.0090	1.7176
		T (°C)	20	5240.0020	5240	0.0020	0.3817
		T (°C)	30	5240.0116	5240	0.0116	2.2137
		T (°C)	40	5240.0132	5240	0.0132	2.5191
		T (°C)	50	5240.0048	5240	0.0048	0.9160
		T (°C)	60	5240.0108	5240	0.0108	2.0611
		T (°C)	70	5240.0001	5240	0.0001	0.0191
Limits				5150-5250 MHz			
Result				Complies			

Temperature:	26 °C	Relative Humidity:	54%RH
Pressure:	101KPa	Test Voltage:	AC120V/60Hz
Test Mode:	TX (5.8G) Mode Frequency U-NII-3 (5745-5825MHz)		

Voltage vs. Frequency Stabilit

TEST CONDITIONS				Reference Frequency: 5745MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5745.00230	5745	0.00230	0.4003
		V max (V)	138.00	5745.00970	5745	0.00970	1.6884
		V min (V)	102.00	5745.00730	5745	0.00730	1.2707
Limits				5725-5850 MHz			
Result				Complies			

Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5745MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5745.00370	5745	0.00370	0.6440
		T (°C)	-10	5745.01200	5745	0.01200	2.0888
		T (°C)	0	5745.01180	5745	0.01180	2.0540
		T (°C)	10	5745.00470	5745	0.00470	0.8181
		T (°C)	20	5745.00590	5745	0.00590	1.0270
		T (°C)	30	5745.00910	5745	0.00910	1.5840
		T (°C)	40	5745.01300	5745	0.01300	2.2628
		T (°C)	50	5745.00670	5745	0.00670	1.1662
		T (°C)	60	5745.01170	5745	0.01170	2.0366
		T (°C)	70	5745.00190	5745	0.00190	0.3307
Limits				5725-5850 MHz			
Result				Complies			

SHENZHEN

Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5785MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5785.00710	5785	0.00710	1.2273
		V max (V)	138.00	5785.00850	5785	0.00850	1.4693
		V min (V)	102.00	5785.00310	5785	0.00310	0.5359
Limits				5725-5850 MHz			
Result				Complies			

Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5785MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5785.00520	5785	0.00520	0.8989
		T (°C)	-10	5785.00500	5785	0.00500	0.8643
		T (°C)	0	5785.01220	5785	0.01220	2.1089
		T (°C)	10	5785.01210	5785	0.01210	2.0916
		T (°C)	20	5785.00060	5785	0.00060	0.1037
		T (°C)	30	5785.00250	5785	0.00250	0.4322
		T (°C)	40	5785.00590	5785	0.00590	1.0199
		T (°C)	50	5785.00220	5785	0.00220	0.3803
		T (°C)	60	5785.00740	5785	0.00740	1.2792
		T (°C)	70	5785.00450	5785	0.00450	0.7779
Limits				5725-5850 MHz			
Result				Complies			

Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5825MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5825.01080	5825	0.01080	1.8541
		V max (V)	138.00	5825.00970	5825	0.00970	1.6652
		V min (V)	102.00	5825.00950	5825	0.00950	1.6309
Limits				5725-5850 MHz			
Result				Complies			

Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5825MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5825.00610	5825	0.00610	1.0472
		T (°C)	-10	5825.01060	5825	0.01060	1.8197
		T (°C)	0	5825.00740	5825	0.00740	1.2704
		T (°C)	10	5825.00880	5825	0.00880	1.5107
		T (°C)	20	5825.00430	5825	0.00430	0.7382
		T (°C)	30	5825.00680	5825	0.00680	1.1674
		T (°C)	40	5825.01000	5825	0.01000	1.7167
		T (°C)	50	5825.00060	5825	0.00060	0.1030
		T (°C)	60	5825.00600	5825	0.00600	1.0300
		T (°C)	70	5825.00700	5825	0.00700	1.2017
Limits				5725-5850 MHz			
Result				Complies			

14. Antenna Requirement

14.1 Limit

15.203 requirement: For intentional device, according to 15.203: an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device.

14.2 Test Antenna

The EUT antenna is Internal antenna, It comply with the standard requirement.

15. EUT Photographs

EUT Photo



NOTE: Appendix-Photographs Of EUT Constructional Details

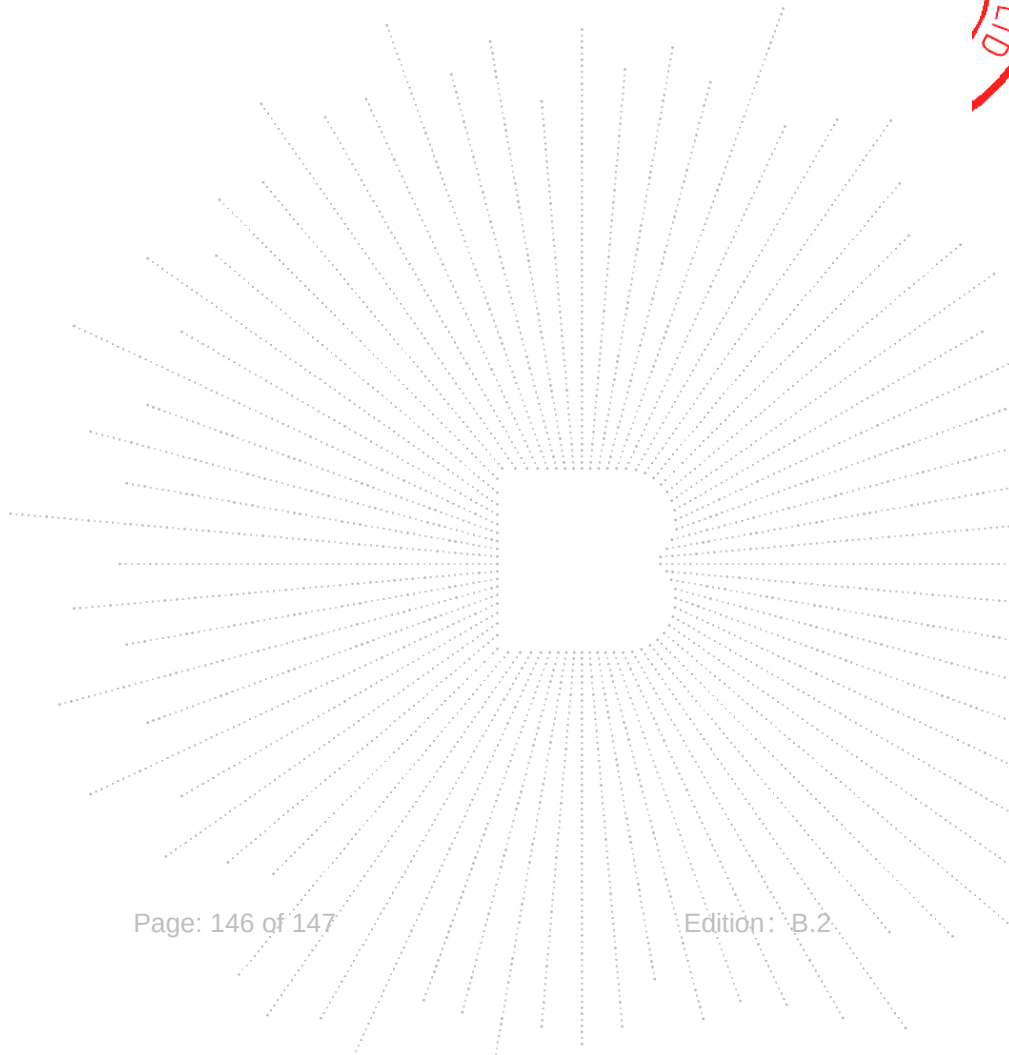
16. EUT Test Setup Photographs

Conducted emissions



Radiated Measurement Photos





STATEMENT

1. The equipment lists are traceable to the national reference standards.
2. The test report can not be partially copied unless prior written approval is issued from our lab.
3. The test report is invalid without the "special seal for inspection and testing".
4. The test report is invalid without the signature of the approver.
5. The test process and test result is only related to the Unit Under Test.
6. Sample information is provided by the client and the laboratory is not responsible for its authenticity.
7. The quality system of our laboratory is in accordance with ISO/IEC17025.
8. If there is any objection to this test report, the client should inform issuing laboratory within 15 days from the date of receiving test report.

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